nPCD

NanoParticle Collection Device for Ultra-Pure Water

New Analytical tool for Rapid Identification of Sub-50 Nanometer Elemental Contamination

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Acknowledgements

- ITRS Committee
- Participating Fabs
- Balazs NanoAnalysis
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Existing Particle Metrology Limits Front End Process Defect Reduction

"The UPW section of Table YE9 highlights the inability of particle metrology in UPW to support the targets established by the Front End Process defect targets. Further work is needed to understand particle deposition from UPW and to speciate organics in UPW."

—ITRS 2008 Update

nPCD is Designed to Address ITRS Particle Metrology Needs by:

- Capturing Particles in UPW
- Retaining and Agglomerating Particles

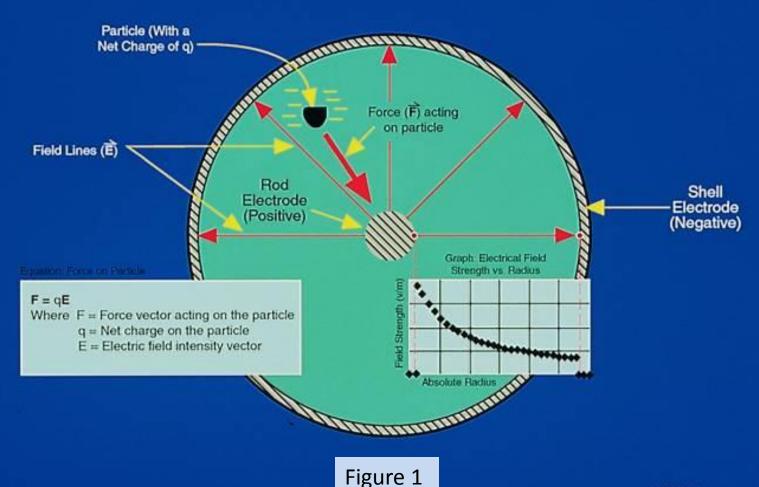
 Releasing Particles to SEM Membranes for Analysis

nPCD is Based on Fundamental Physics

- Ultra-Pure Water is relatively non-conductive so we can establish an electric field in it
- Majority of particles in ultra-pure water have electrical charge
- Using proper electrical and hydraulic design, *n*PCD removes particles from ultra-pure water

Electrical Design of the *n*PCD

Electromagnetic Field moves charged particles through UPW

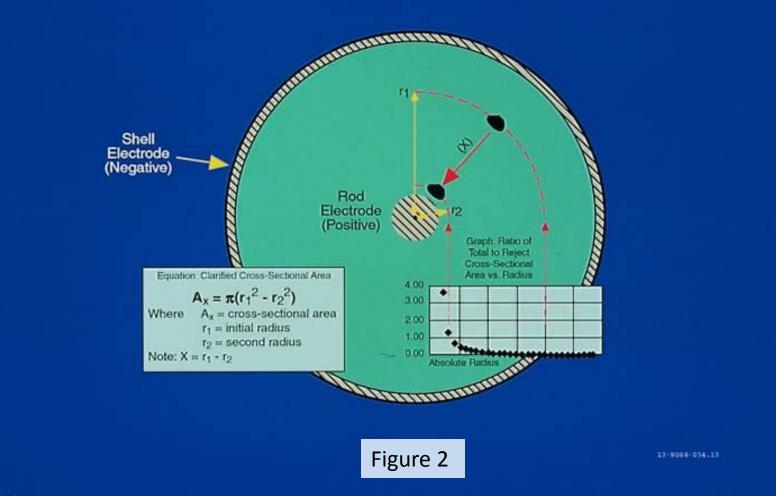


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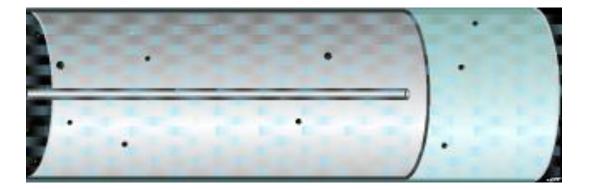
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Hydraulic Design of the *n*PCD

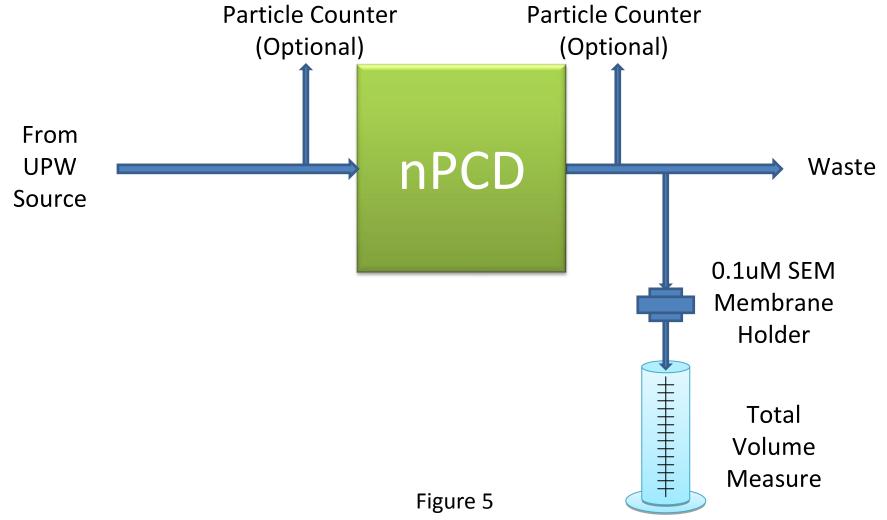
Laminar Flow and Radial Separation Efficiently Capture Particles



The rod captures nanoparticles, then ejects them as larger agglomerates for collection on a membrane.



Traditional 0.1 Micron Sample Membranes Collect Concentrated Contamination for SEM/EDS Analysis

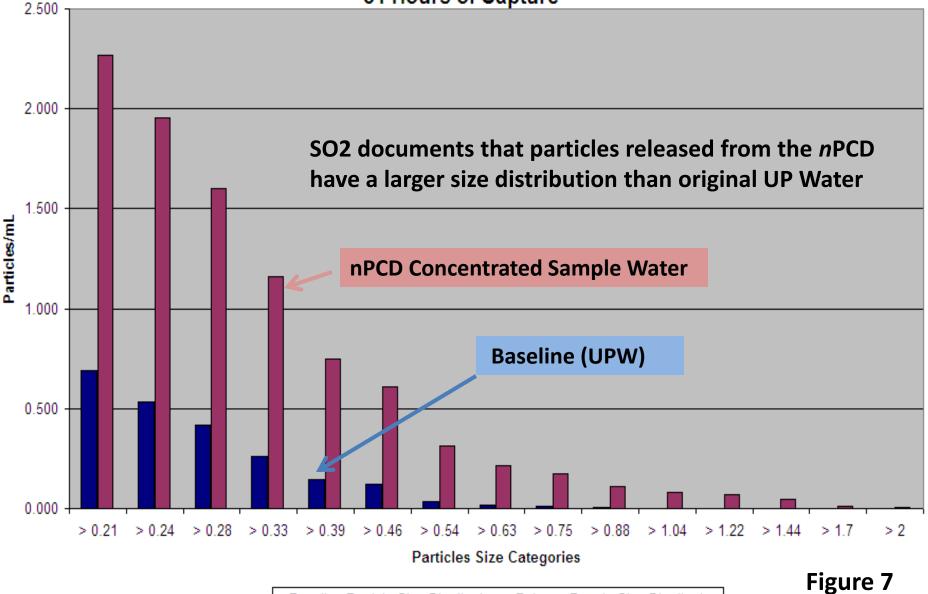


nPCD is Built for UPW Service

Separate Boxes Contain Wetted and Electrical Systems Wetted Materials Include PFA, PVDF, and Electropolished 316L Stainless Steel



n PCD Aggomerates Sub-50 Nanometer Particles PMS SO2 Laser Particle Counter 51 Hours of Capture

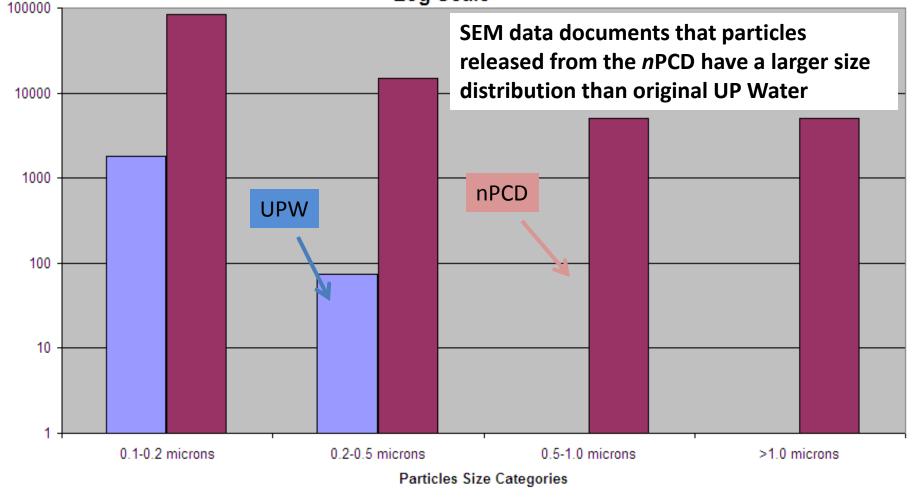


■ Baseline Particle Size Distribution ■ Release Partcle Size Distribution

n PCD Aggomerates Sub-50 Nanometer Particles

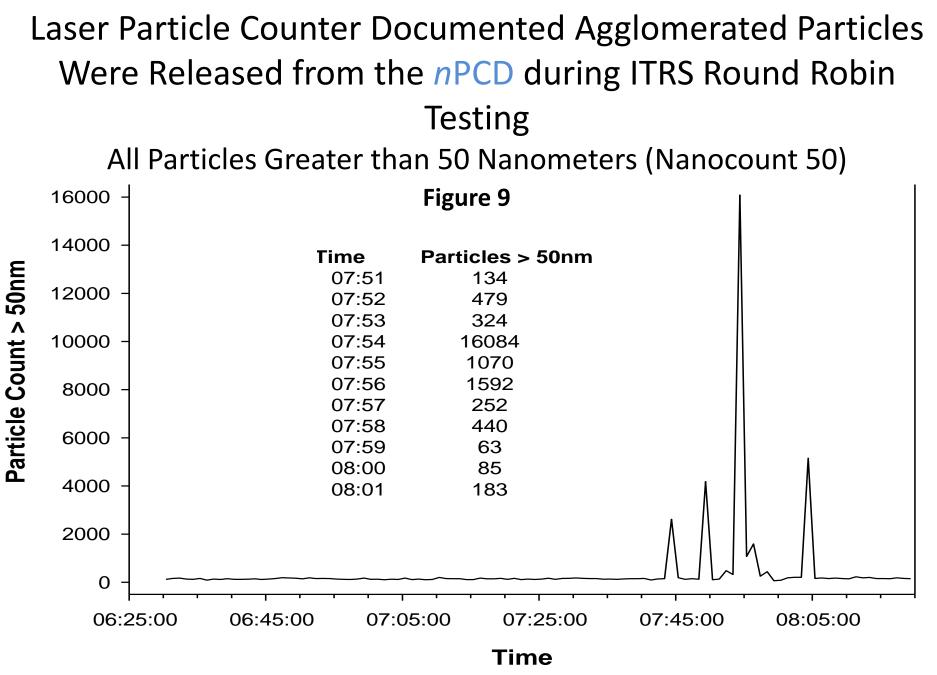
SEM Membrane Particle Data Capture Time of 44.3 Hours

Log Scale



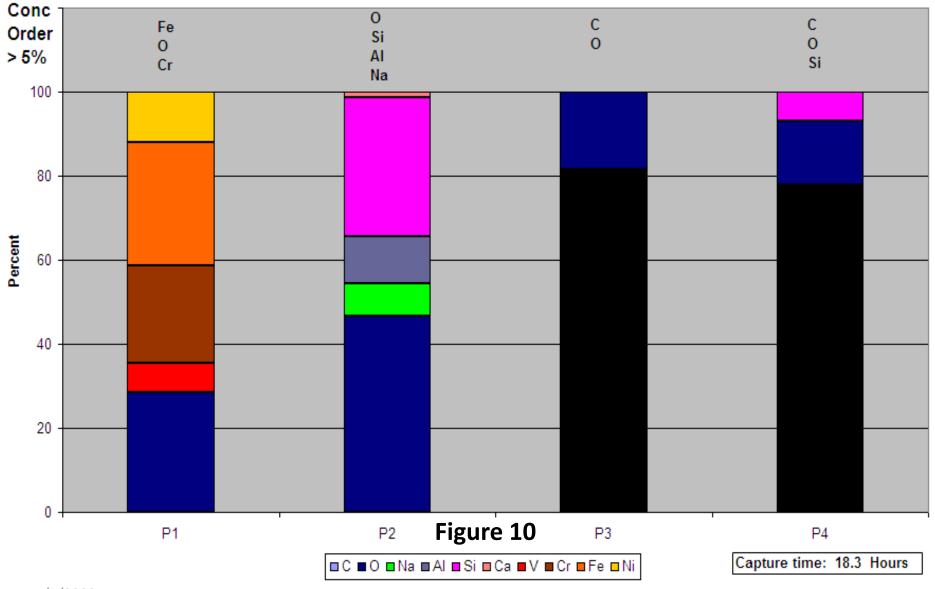
■ Baseline Particle Size Distribution ■ Release Partcle Size Distribution

Particles/mL



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nPCD Identified Elemental Composition of UPW Particles during ITRS Round Robin Percent Elemental Concentration in Particles



nPCD Testing Identified a Large Variety of Elements in UPW

- Carbon
- Nitrogen
- Oxygen
- Fluorine
- Sodium
- Magnesium
- Aluminum

- Silica
- Phosphorus
- Sulfur
- Chloride
- Potassium
- Calcium
- Titanium

- Vanadium
- Chromium
- Iron
- Nickel
- Zinc
- Bromine
- Antimony

nPCD Testing Identified the Most Common Nano-Contaminants in UPW

• Carbon/Oxygen

• Silica /Oxygen/Aluminum

Iron/Chromium/Nickel/Oxygen

• Fluorine/Carbon/Oxygen

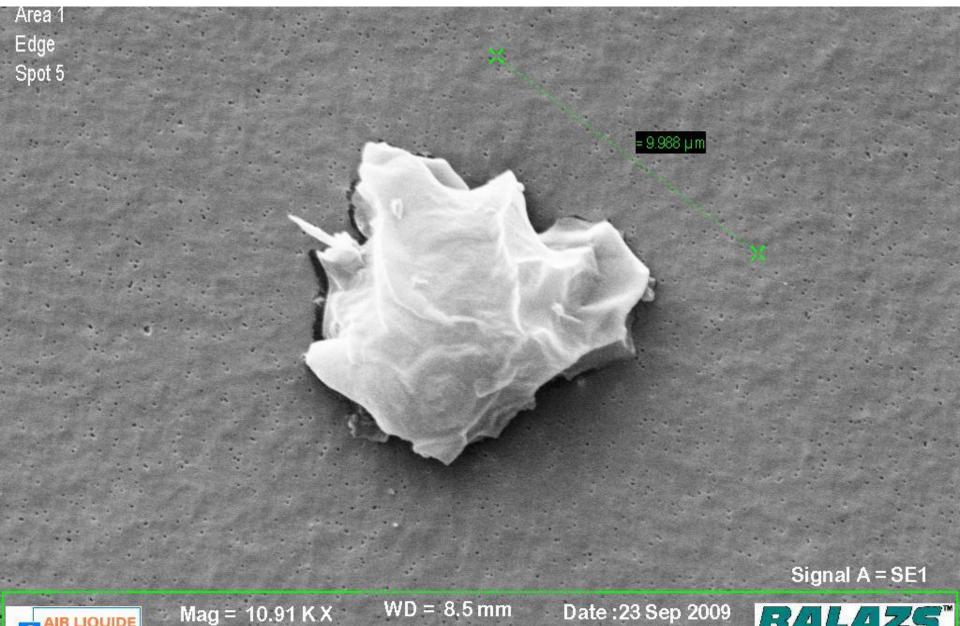
nPCD Collects Particles for Visual and Elemental Analysis Carbon Particle – Bacterial Shape



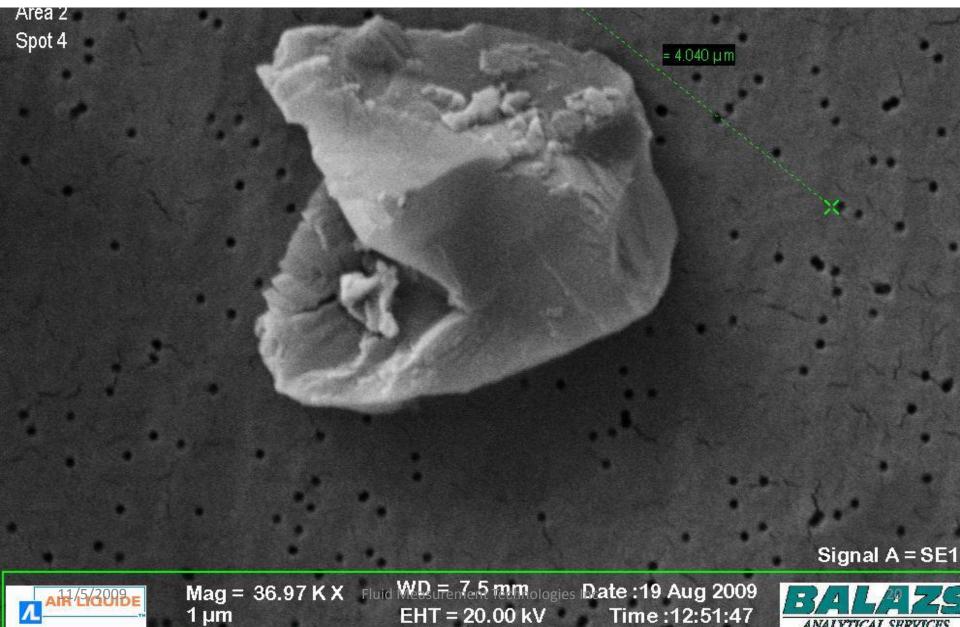
nPCD Collects Particles for Visual and Elemental Analysis Carbon Particle – Biological Material

Spot 9 =4.901 µm Signal A = SE1 $WD = 7.0 \, mm$ Date :19 Aug 2009 Mag = 20.43 K X $EHT = 20.00 \, kV$ Time :10:50:19 1 µm 11/5/2009 ANALYTICAL SER

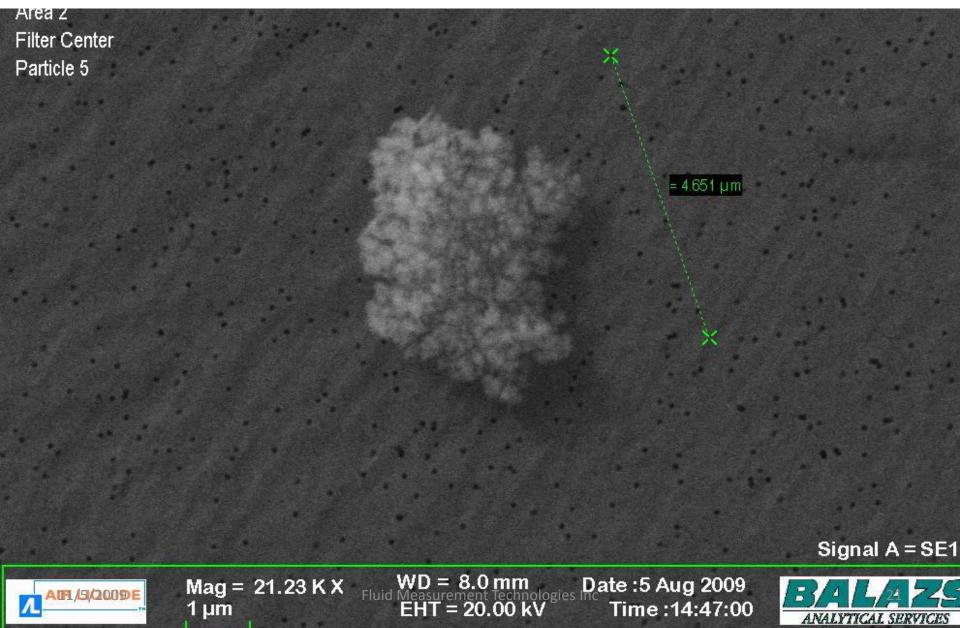
nPCD Collects Particles for Visual and Elemental Analysis Silica/Oxygen Particle



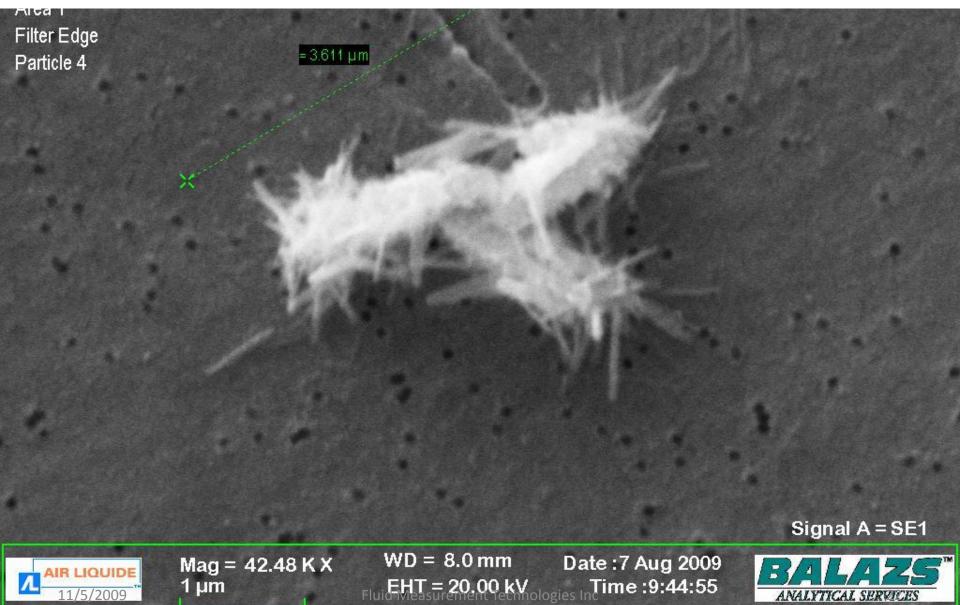
nPCD Collects Particles for Visual and Elemental Analysis Silica/Aluminum/Potassium/Oxygen Particle



nPCD Collects Particles for Visual and Elemental Analysis Iron/Chrome/Nickel/Oxygen Particle – Type One



nPCD Collects Particles for Visual and Elemental Analysis Iron/Chrome/Oxygen Particle – Type Two



nPCD Collects Particles for Visual and Elemental Analysis Fluorine/Carbon/Oxygen Particle



The *n*PCD Is a New Analytical Tool That Rapidly Identifies Sub-50 nm Elemental Contamination.

•Captures and Agglomerates Particles below 50 nm

•Enables visible and elemental identification of contamination

•Leverages and enhances proven SEM/EDS analysis

•Supports particle concentration and mass data calculation

•Provides fast and actionable data

•Standardizes data between process points and facilities

nPCD Supports the ITRS 2008 Front End Process Particle Metrology Needs for Ultrapure Water Process Control and Front End Defect Reduction

The next paper will provide specific elemental contaminant identification from five ITRS member fabs.